SLOVENSKI STANDARD
SIST EN 62047-20:2014

01-november-2014

Polprevodniški elementi - Mikroelektromehanski elementi - 20. del: Žiroskopi (IEC 62047-20:2014)

Semiconductor devices - Micro-electromechanical devices - Part 20: Gyroscopes

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ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general

SIST EN 62047-20:2014 **en**

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EN 62047-20

September 2014

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English Version

Semiconductor devices - Micro-electromechanical devices - Part 20: Gyroscopes (IEC 62047-20:2014)

Dispositifs à semiconducteurs - Dispositifs microélectromécaniques - Partie 20: Gyroscopes (CEI 62047-20:2014)

Halbleiterbauelemente - Bauelemente der Mikrosystemtechnik - Teil 20: Gyroskope (IEC 62047-20:2014)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47F/188/FDIS, future edition 1 of IEC 62047-20, prepared by SC 47F "Microelectromechanical systems" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62047-20:2014.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2015-04-30
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2017-07-31

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IEC 62047-20

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

colour inside

Semiconductor devices – Micro-electromechanical devices – Part 20: Gyroscopes

Dispositifs à semiconducteurs – Dispositifs microélectromécaniques – Partie 20: Gyroscopes

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

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FOREWORD

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International Standard IEC 62047-20 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47F/188/FDIS	47F/191/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62047 series, published under the general title *Semiconductor devices – Micro-electromechanical devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

1 Scope

This part of IEC 62047 specifies terms and definitions, ratings and characteristics, and measuring methods of gyroscopes.

Gyroscopes are primarily used for consumer, general industries and aerospace applications. MEMS and semiconductor lasers are widely used for device technology of gyroscopes.

Hereafter, gyroscope is referred to as gyro.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

None

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1
rotating table
rate table
rotating tool on which a gyro is loaded during measurement

3.2
earth rate
angular rate generated in inertial space due to the rotation of the earth

Note 1 to entry: When the angular rate in inertial space is defined as stellar day 23 hours, 56 minutes, a reference of 4,098 903 691 seconds is obtained as specified by the International Earth Rotation and Reference Systems Service (IERS) and therefore, the angular rate of Earth in inertial space is approximately 15,04 °/h. For details of the definition, refer to the IERS website (http://www.iers.org).

3.3
scale factor
ratio of gyro output voltage or output digital signal versus the rotating angular rate being applied, described in unit: V/(°/s) or bit/(°/s)

4 Essential ratings and characteristics

4.1 Categorization of gyro

Table 1 shows uses of gyro categorized by application fields.

Table 1 – Categories of gyro

Category	Contents
1	primarily for consumer use where variations of bias are not specified
2	primarily for industrial use where designing with appropriate range of values of variations of bias
3	primarily for aerospace use where designing with detectable function of the earth rate

4.2 Absolute maximum ratings

Table 2 describes absolute maximum ratings of gyro.

The following items listed in the table shall be described in the specification, unless otherwise stated in the relevant procurement specifications. Stresses over these limits can be one of the causes of permanent damage to the devices.

Table 2 – Absolute maximum ratings

Item no	Absolute maximum ratings	Category			Specification			Unit	Remarks
		1	2	3	min	typ	max		
4.2.1	Storage temperature range	x	x	x	x		x	°C	
4.2.2	Operating temperature range	x	x	x	x		x	°C	
4.2.3	Storage humidity range							%	Moisture absorption management level (for example, see levels specified in Table 5-1 "Moisture Sensitivity Levels" of page 7 in IPC/JEDEC J-STD-020C, [1] [1]) for reflow soldering shall be specified. Those descriptions shall not be provided to devices applied with no reflow soldering process and/or hermetic seal packaging process.
4.2.4	Mechanical shock in operating state	x	x	x			x	m/s^2	Maximum limiting value of mechanical shock which does not cause permanent damage to devices under an appropriate operating state. Acceleration, times and wave forms shall be specified.
4.2.5	Mechanical shock in non operating state	x	x	x			x	m/s^2	Maximum limiting value of mechanical shock which does not cause permanent damage to devices under an appropriate non-operating state. Acceleration, times and wave forms shall be specified.
4.2.6	Mechanical vibration in operating state	x	x	x			x	m/s^2	Maximum limiting value of mechanical vibration acceleration and frequency which does not cause permanent damage to devices under an appropriate operating state.
4.2.7	Mechanical vibration in non operating state	x	x	x			x	m/s^2	Maximum limiting value of mechanical vibration acceleration and frequency which does not cause permanent damage to devices under an appropriate non-operating state.
4.2.8	Angular rate limit	x	x	x			x	°/s	Maximum limiting value of angular rate which does not cause permanent damage to devices under an appropriate operating state.

1 Numbers in square brackets refer to the Bibliography.

Item no	Absolute maximum ratings	Category			Specification			Unit	Remarks
		1	2	3	min	typ	max		
4.2.9	Angular acceleration limit	x	x	x			x	°/s^2	Maximum limiting value of angular acceleration which does not cause permanent damage to devices under an appropriate operating state.
4.2.10	Maximum supply voltage	x	x	x			x	V	Maximum limiting value of supply voltage which does not cause permanent damage to devices.
4.2.11	Maximum supply current						x	A	Maximum limiting value of supply current which does not cause permanent damage to devices. This limiting value shall be specified only for a kind of constant current driving devices.
NOTE x: mandatory, blank: optional									

4.3 Normal operating rating

Table 3 describes normal operating ratings of gyro.

The following items should be described in the specification, unless otherwise stated in the relevant procurement specifications. These conditions are recommended to keep specified characteristics in stable state during operations of applying devices.

Table 3 – Normal operating ratings

Item no.	Normal operating ratings	Category			Specification			Unit	Remarks
		1	2	3	min	typ	max		
4.3.1	Guarantee operating temperature range	x	x	x	x		x	°C	
4.3.2	Guarantee operating humidity range	x	x	x			x	%	
4.3.3	Supply voltage range	x	x	x	x	x	x	V	
4.3.4	Current consumption	x	x	x			x	A	
4.3.5	Start up current			x			x	A	
4.3.6	Power supply ripple requirement			x			x	Vpp	
4.3.7	Other environmental condition				x		x		Recommended ranges of appropriate indexes of environmental conditions (such as conditions of electromagnetic environments, air pressure) specified as a specified minimum value to maximum value.
4.3.8	Overload recovering time			x			x	s	Maximum value of overload recovering time in the range of measurement less than maximum rating.
NOTE x: mandatory, blank: optional									

4.4 Characteristics

Table 4 describes characteristics of gyro.

Table 4 – Characteristics

Item no	Characteristics	Category 1	Category 2	Category 3	Specification min	Specification typ	Specification max	Unit	Remarks
4.4.1	Measurement range	x	x	x			x	°/s	Angular rate measuring range for guarantee of performance
4.4.2	Nominal scale factor	x	x	x		x		V/(°/s) or bit/(°/s)	Nominal scale factor is also called as standard sensitivity.
4.4.3	Initial scale factor variation		x	x	x		x	%	Minimum and maximum value of variation from standard sensitivity at a specified temperature
4.4.4	Scale factor variation with temperature or Temperature coefficient of scale factor		x	x	x		x	%	Minimum and maximum value of standard sensitivity under a specified variation in temperature
4.4.5	Ratiometric error for scale factor			x			x	%	Maximum value of error of sensitivity applying voltage fluctuation caused by operating instability of applying electric power supply
4.4.6	Linearity						x	%	
4.4.7	Scale factor stability	n		x		x			A typical value of stability of sensitivity under a specified definite input voltage value
4.4.8	Scale factor symmetry	n		x		x			A typical value of asymmetry of sensitivity defined as a ratio of the sensitivity applying plus value of a specified input voltage to minus value of a specified input voltage, see 5.1.3.8.
4.4.9	Cross axis sensitivity			x			x	%	Maximum value of sensitivity of cross axis (see 5.2.3 Principle of measurement).
4.4.10	Nominal bias	x	x	x		x		V or bit	Typical value of bias voltage or bit value under an appropriate applying input voltage value
4.4.11	Initial bias variation			x	x		x	°/s	Minimum and maximum value of bias under a specified temperature
4.4.12	Bias variation with temperature or Temperature coefficient of bias			x	x		x	°/s	Minimum and maximum value of standard bias under a specified variation in temperature
4.4.13	Ratiometric error for bias			x			x	V	Maximum value of error of bias applying voltage fluctuation caused by operating instability of applying electric power supply. No description is required for digital output case.
4.4.14	Bias repeatability (switch on to switch off)			x	x		x	°/s	Minimum value and maximum value of bias fluctuation of each period during a switching on state to a switching off state
4.4.15	Bias hysteresis			x			x	°/s	Maximum value of hysteresis of bias under a specified variation in temperature
4.4.16	Linear g sensitivity			x			x		Maximum value of changed bias value under operating conditions of a specified constant acceleration value, expressed in comparison with *g*((°/s)/*g*)

Item no	Characteristics	Category			Specification			Unit	Remarks
		1	2	3	min	typ	max		
4.4.17	Bias drift after power on			x			x	°/s	Maximum value of drift of bias during turned on state of applying electric power supply
4.4.18	In-band noise			x			x	°/s	In-band output noise at stable state operation, described with RMS
4.4.19	Broadband noise			x			x	°/s	Broadband output noise at stable state operation, described with RMS
4.4.20	Angular random walk			x			x	°/√h or (°/h)/√Hz	Output variation of gyroscope due to noise, described with RMS
4.4.21	Bias instability			x			x	°/s	Described with RMS
4.4.22	Start up time			x			x	s	Time required for the gyro output to reach the specified output after power on
4.4.23	Frequency band	x	x	x	x			Hz	Frequency response characteristics
4.4.24	Gain peak						x	dB	Maximum value of gain of frequency characteristics under a specified frequency. Describe with a specified value of the frequency (Hz).
4.4.25	Resolution			x	x			°/s	Detectable minimum change in the input angular rate
NOTE x: mandatory, blank: optional, n: unnecessary									

5 Measuring methods

5.1 Scale factor

5.1.1 Purpose

To specify measuring method relating to scale factor in gyro.

5.1.2 Measuring circuit (circuit diagram)

Figure 1 shows an example of composition of the sensitivity measuring circuit and Figure 2 shows an example of wiring configuration. The measuring circuit is composed of the gyro to be measured and the devices listed below. Components to apply in the measuring circuit shall satisfy the points described below.

– Temperature controlled chamber: This should be capable of maintaining the gyro at a specified ambient temperature. Furthermore, the temperature control range should be wider than the operating temperature range of gyro.

– Temperature sensor: This should be capable of measuring the temperature in the temperature controlled chamber. A temperature sensor provided in advance in the temperature controlled chamber can be used.

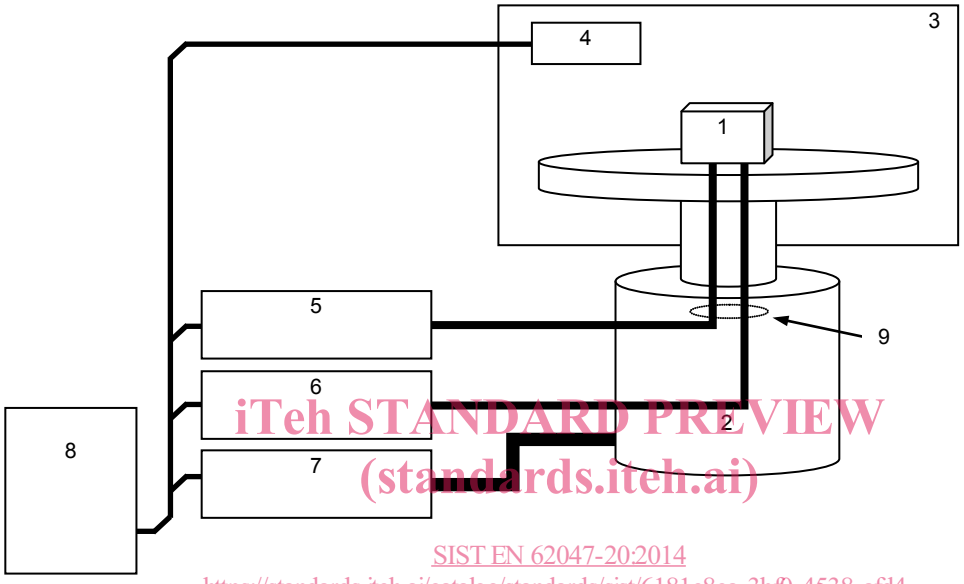
– Power supply for gyro: This should be capable of supplying the voltage and current required by gyro. The fluctuating range for ripple voltage on the output should meet the gyro requirements in the supplying state.

– Data acquisition system: Measuring device or measuring system adjusted to the output configuration of gyro. For example, a digital multimeter or data logger is used if gyro output is analogue voltage.

– Rotating table control device: Control device which controls the input angular rate given to the rating table. This table is given an angular rate of rotation that is not less than the detection range of gyro, and that is capable of accommodating changes in the angular rate corresponding to the minimum resolution. See Annex A for measurement accuracy of the rotating table.

– Measuring system controller: An overall system for automatic control of the power supply, gyro, data acquisition system and rotating table control device. This is not required for manual operation.

– Slip ring: It should be noted that the slip ring can be a source of noise generation.



Key

1	DUT, a piece of gyro
2	rate table
3	temperature controlled chamber, to keep a specified temperature value of DUT
4	temperature sensor, to monitor environmental temperature in a chamber
5	power supply to operate DUT
6	data logger, to obtain data during the measurement
7	controller for rate table, to set up a specified rotating condition of the rate table
8	control system, to control the measuring circuit during the measurement
9	slip ring

Figure 1 – Example of measuring circuit